## Question 1:

Tabularized are the results obtained from the kNN classifiers using the Euclidean distance metric:

k	Training error	Testing Error	Fitting	Variance	Bias
1	0.0000	0.2200	Overfitting	High	Low
3	0.1435	0.2050	Overfitting	High	Low
5	0.1561	0.1700	Fitting	Balanced	Balanced
10	0.1519	0.1700	Fitting	Balanced	Balanced
20	0.1688	0.1700	Fitting	Balanced	Balanced
30	0.1688	0.1600	Fitting	Optimal	Optimal
50	0.1582	0.1900	Underfitting	Low	High
100	0.1962	0.2000	Underfitting	Low	High
150	0.1920	0.1900	Underfitting	Low	High
200	0.2215	0.2050	Underfitting	Low	High

Understandably, the kNN models using  $\mathbf{k} = 1$  and  $\mathbf{k} = 3$  generated extremely low training errors, but considerably high test errors. We can confidently flag these models as **Overfitting**, having high variance and low bias. That is, introducing new data points or changing the training data will probably lead to vast changes in the predictions made by these models.

On the other hand, the models with values of  $\mathbf{k} = 50$ , 100, 150 and 200 generated both high training errors and high test errors. These models can be labeled as **Underfitting**, having high bias (towards the particular training data) and low variance to changes in the training dataset.

However, the ideal values of k = 5, 10, 20, 30 led to models that generated consistently low training errors but, more importantly, low test errors as well; with k = 30 yielding the **lowest** test error rate.

## Question 2:

In Question 1, using k = 30 with the Euclidean distance metric yielded the best performance, with the training error rate being **0.1688** and the test error rate being **0.1600**.

Simply replacing the metric with the Manhattan distance, and keeping  $\mathbf{k} = 30$ , we observed a decrease in performance compared to the Euclidean distance metric; the training error rate dropped to **0.1646**, but the test error rate rose to **0.1650**.

## Question 3:

Although the Euclidean distance metric generates the **lowest** test error rate of the two metrics, on average (**0.188** v. **0.165**), across all values of **k**, the Manhattan metric yields the **lower** test error rate.

As such, we utilized the Manhattan metric in generating the plots of the capacity log(1/k) against the training and test error rates.

Rightmost are the overfitting models with  $\mathbf{k} = 1$ , 3 as discussed in Question 1. Due to the low bias/high variance that models in this region possess, they are also more likely to fit a wider variety of functions; that is, they possess **high capacity**.

Leftmost are the opposite, underfitting models. They possess **low capacity** due to their high bias and low variance; they are unable to generalize or fit well to unseen or new training data.

The models in the middle can be said to be of **optimal capacity**, balanced variance and balanced bias. While the training error is not necessarily the **lowest**, they **sufficiently** generalize to unseen instances/test data.

## **Question 4:**

Due to the numerical (non-categorical) natures of the features, `x1` and `x2`, methods such as frequency, label, one-hot (OHE) and ordinal encoding are not effective.

One possible source of performance improvement would be via scaling techniques, since kNN is a classification method. As such, we plotted the distributions of the two attributes, 'x1' and 'x2', to get a better overview of the shape of the values, and to assist in picking appropriate scaling techniques.

Plotting the distributions revealed two things:

- the presence of outliers;
- both attributes to be normally distributed, having narrow Gaussians; we picked the FunctionTransformer(),

The outliers were removed and the training set was scaled. Subsequently, a grid search was performed to determine the optimum parameters to pass into the **kNN** model. The image below shows the ideal params, as well as the improved training error from Question 2 (**0.1688** v. **0.1561**), but an increase in the test error (**0.1600** v. **0.165**).